

Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark Office

Attorney's Docket No.

09712-124001

Application No.

09/879,428

**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant

Henry A. Hill

Filing Date

June 12, 2001

Group Art Unit

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
JRA	AA	4,948,254	08/1990	Ishida			
	AB	5,331,400	07/1994	Wilkening et al.			
	AC	5,404,222	04/1995	Lis			
	AD	5,483,343	01/1996	Iwamoto et al.			
	AE	5,663,893	09/1997	de Groot			
	AF	6,008,902	12/1999	Rinn			
	AG	6,137,574	10/2000	Hill			
	AH	6,181,420	01/2001	Badami et al.			
	AI	6,252,668	06/2001	Hill			
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
JRA	AL	351078	12/1995	Japan				
	AM	117083	04/1996	Japan				
	AN							
	AO							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
JRA	AP	Badami V.B. et al., "Investigation of Nonlinearity in High Accuracy Heterodyne Laser Interferometry," 1997 Proceedings, Vol. 16, pp. 153-156.
	AQ	Wu, C.M. et al., Analytical Modeling of the Periodic Nonlinearity in Heterodyne Interferometry" Applied Optics, Vol. 37, No. 28, October 1, 1998, pp. 6696-6700.
	AR	Oka K. et al., "Polarization Heterodyne Interferometry Using Another local Oscillator Beam," Optics Communications, 92 (1982), 1-5.
	AS	Hines, B. et al., "Sub-Nanometer Laser Metrology--Some Techniques and Models," Jet Propulsion Laboratory, California Institute of Technology, pp. 1195-1204.
	AT	Bobroff, N., "Recent Advances in Displacement Measuring Interferometry," Measurement Science & Technology, Vol. 4, Lo. 9, September 1993, pp. 907-926.

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.